

Welcome to Galaxy Examinator reports

Date: Mon Sep 2 23:42:12 2024

Product: LotID:

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Tests Statistics

Pareto lists: Tests Cp , Tests Cpk , Failures , Failure Signatures , Software Bin , Hardware Bin

Wafermaps & Strip Maps Bins (Software, Hardware) Message Log: Empty



Tests Statistics

| Test | Name | Type | Low L. | High L. | Source | Execs | Fails | Mean | Sigma | Ср | Cpk | Yield |
|-----------|------------------------------|------|----------|----------|---------|-------|-------|----------------|---------------|--------|--------|----------|
| 0 | Functional_T1 | F | n/a . | n/a . | Samples | 5 | 0 | n/a . | n/a . | n/a . | n/a . | 100.00 % |
| 1 | Functional_T2 | F | n/a . | n/a . | Samples | 5 | 0 | n/a . | n/a . | n/a . | n/a . | 100.00 % |
| 2 | Functional_T3 | F | n/a . | n/a . | Samples | 5 | 0 | n/a . | n/a . | n/a . | n/a . | 100.00 % |
| <u>3</u> | PinPMU p20 19.g128 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -639.417 mV | 0.348026 mV | 526.8 | 516.6 | 100.00 % |
| <u>4</u> | PinPMU p21 19.g126 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -639.519 mV | 0.522085 mV | 351.2 | 344.5 | 100.00 % |
| <u>5</u> | PinPMU p22 19.e126 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -639.257 mV | 0.334326 mV | 548.4 | 537.7 | 100.00 % |
| <u>6</u> | PinPMU p23 19.e124 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -639.195 mV | 0.807619 mV | 227.0 | 222.5 | 100.00 % |
| <u>7</u> | PinPMU p40 19.e130 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -640.081 mV | 0.48976 mV | 374.3 | 367.6 | 100.00 % |
| <u>8</u> | PinPMU p41 19.e139 | P | -1200 mV | -100 mV | Samples | 5 | 0 | −640.195 mV | 0.426269 mV | 430.1 | 422.4 | 100.00 % |
| 9 | PinPMU p42 19.e147 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -640.953 mV | 0.272958 mV | 671.7 | 660.6 | 100.00 % |
| <u>10</u> | PinPMU p43 19.e151 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -640.523 mV | 0.167282 mV | 1096.0 | 1077.1 | 100.00 % |
| <u>11</u> | PinPMU p50 19.e128 | P | -1200 mV | -100 mV | Samples | 5 | 0 | −639.475 mV | 0.241413 mV | 759.4 | 744.9 | 100.00 % |
| <u>12</u> | PinPMU p51 19.g149 | P | -1200 mV | -100 mV | Samples | 5 | 0 | −635.25 mV | 0.409467 mV | 447.7 | 435.7 | 100.00 % |
| <u>13</u> | PinPMU p52 19.e137 | P | -1200 mV | -100 mV | Samples | 5 | 0 | −638.154 mV | 0.367656 mV | 498.7 | 487.9 | 100.00 % |
| <u>14</u> | PinPMU p53 19.e135 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -638.36 mV | 0.539505 mV | 339.8 | 332.6 | 100.00 % |
| <u>15</u> | PinPMU p60 19.g130 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -637.663 mV | 0.634843 mV | 288.8 | 282.3 | 100.00 % |
| <u>16</u> | PinPMU p61 19.g104 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -638.113 mV | 0.499234 mV | 367.2 | 359.3 | 100.00 % |
| <u>17</u> | PinPMU p62 19.g102 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -638.369 mV | 0.277231 mV | 661.3 | 647.3 | 100.00 % |
| <u>18</u> | PinPMU p63 19.e102 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -638.071 mV | 0.41227 mV | 444.7 | 435.0 | 100.00 % |
| <u>19</u> | PinPMU p70 19.g139 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -639.844 mV | 0.642248 mV | 285.5 | 280.2 | 100.00 % |
| <u>20</u> | PinPMU p71 19.g147 | P | -1200 mV | -100 mV | Samples | 5 | 0 | −638.457 mV | 0.33091 mV | 554.0 | 542.4 | 100.00 % |
| <u>21</u> | PinPMU p72 19.e104 | P | -1200 mV | -100 mV | Samples | 5 | 0 | −637.545 mV | 0.312858 mV | 586.0 | 572.7 | 100.00 % |
| <u>22</u> | PinPMU p73 19.e108 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -637.529 mV | 0.312762 mV | 586.2 | 572.9 | 100.00 % |
| <u>23</u> | PinPMU cs 19.g106 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -637.549 mV | 0.255428 mV | 717.7 | 701.5 | 100.00 % |
| <u>24</u> | PinPMU prog 19.g124 | P | -1200 mV | -100 mV | Samples | 5 | 0 | -638.972 mV | 0.596923 mV | 307.1 | 301.0 | 100.00 % |
| <u>25</u> | SeqLeakage1 p20 19.g128 | P | -30 uA | 10 uA | Samples | 5 | 0 | -0.665264 uA | 0.00794774 uA | 838.8 | 447.3 | 100.00 % |
| <u>26</u> | SeqLeakage1 p21 19.g126 | P | -30 uA | 10 uA | Samples | 5 | 0 | -0.664335 uA | 0.00677483 uA | 984.0 | 524.7 | 100.00 % |
| <u>27</u> | SeqLeakage1 p22 19.e126 | P | -30 uA | 10 uA | Samples | 5 | 0 | -0.671868 uA | 0.00990592 uA | 673.0 | 359.1 | 100.00 % |
| <u>28</u> | SeqLeakage1 p23 19.e124 | P | -30 uA | 10 uA | Samples | 5 | 0 | -0.673144 uA | 0.0106867 uA | 623.8 | 332.9 | 100.00 % |
| <u>29</u> | SeqLeakage2 cs 19.g106 | P | -30 uA | 10 uA | Samples | 5 | 0 | 0.00283109 uA | 0.00491731 uA | 1355.8 | 677.7 | 100.00 % |
| <u>30</u> | SeqLeakage2 prog 19.g124 | P | -30 uA | 10 uA | Samples | 5 | 0 | -0.00320883 uA | 0.00660766 uA | 1008.9 | 504.6 | 100.00 % |
| <u>31</u> | VBT_outpleakage1 p40 19.e130 | P | –10 uA | 20 uA | Samples | 5 | 0 | -0.00436721 uA | 0.0100862 uA | 495.7 | 330.3 | 100.00 % |
| Test | Name | Type | Low L. | High L. | Source | Execs | Fails | Mean | Sigma | Ср | Cpk | Yield |
| <u>32</u> | VBT_outpleakage1 p41 19.e139 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00244967 uA | 0.00566692 uA | 882.3 | 588.4 | 100.00 % |
| <u>33</u> | VBT_outpleakage1 p42 19.e147 | P | -10 uA | 20 uA | Samples | 5 | 0 | -0.00129372 uA | 0.0100471 uA | 497.7 | 331.7 | 100.00 % |
| <u>34</u> | VBT_outpleakage1 p43 19.e151 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00512209 uA | 0.00699416 uA | 714.9 | 476.8 | 100.00 % |
| <u>35</u> | VBT_outpleakage1 p50 19.e128 | P | –10 uA | 20 uA | Samples | 5 | 0 | -0.00182717 uA | 0.0112614 uA | 444.0 | 295.9 | 100.00 % |
| <u>36</u> | VBT_outpleakage1 p51 19.g149 | P | −10 uA | 20 uA | Samples | 5 | 0 | 0.00252539 uA | 0.0140381 uA | 356.2 | 237.5 | 100.00 % |

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| 25 | VDE - 1 1 1 52 10 127 | ъ. | 10. 4 | 20. 4 | 0 1 | ~ | 0 | 0.00220724 | 0.0105120 | 475.6 | 217.0 | 100.00.00 |
|--|---|--|--|---|---|---|---|--|--|--|---|---|
| <u>37</u> | VBT_outpleakage1 p52 19.e137 | P | -10 uA | 20 uA | Samples | 5 | 0 | -0.00229734 uA | 0.0105138 uA | 475.6 | 317.0 | 100.00 % |
| <u>38</u> | VBT_outpleakage1 p53 19.e135 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00396093 uA | 0.00320465 uA | 1560.2 | 1040.6 | 100.00 % |
| <u>39</u> | VBT_outpleakage1 p60 19.g130 | P | -10 uA | 20 uA | Samples | 5 | 0 | -0.0143868 uA | 0.0136743 uA | 365.6 | 243.4 | 100.00 % |
| <u>40</u> | VBT_outpleakage1 p61 19.g104 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.0028242 uA | 0.00979879 uA | 510.3 | 340.3 | 100.00 % |
| <u>41</u> | VBT_outpleakage1 p62 19.g102 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00956627 uA | 0.00491822 uA | 1016.6 | 678.4 | 100.00 % |
| <u>42</u> | VBT_outpleakage1 p63 19.e102 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00556653 uA | 0.00375119 uA | 1332.9 | 889.1 | 100.00 % |
| <u>43</u> | VBT_outpleakage1 p70 19.g139 | P | -10 uA | 20 uA | Samples | 5 | 0 | -0.00510874 uA | 0.00834578 uA | 599.1 | 399.2 | 100.00 % |
| <u>44</u> | VBT_outpleakage1 p71 19.g147 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.000996936 uA | 0.00991909 uA | 504.1 | 336.1 | 100.00 % |
| <u>45</u> | VBT_outpleakage1 p72 19.e104 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00106722 uA | 0.00886694 uA | 563.9 | 376.0 | 100.00 % |
| <u>46</u> | VBT_outpleakage1 p73 19.e108 | P | -10 uA | 20 uA | Samples | 5 | 0 | -0.00449732 uA | 0.0126796 uA | 394.3 | 262.8 | 100.00 % |
| <u>47</u> | OutputZ_leak_vbt1 p40 19.e130 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.000842794 uA | 0.00616284 uA | 811.3 | 540.9 | 100.00 % |
| <u>48</u> | OutputZ_leak_vbt1 p41 19.e139 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.000612416 uA | 0.010552 uA | 473.8 | 315.9 | 100.00 % |
| <u>49</u> | OutputZ_leak_vbt1 p42 19.e147 | P | –10 uA | 20 uA | Samples | 5 | 0 | 0.00418555 uA | 0.0104289 uA | 479.4 | 319.8 | 100.00 % |
| <u>50</u> | OutputZ_leak_vbt1 p43 19.e151 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00634528 uA | 0.0106673 uA | 468.7 | 312.7 | 100.00 % |
| <u>51</u> | OutputZ_leak_vbt1 p50 19.e128 | P | -10 uA | 20 uA | Samples | 5 | 0 | -0.000609058 uA | 0.00665885 uA | 750.9 | 500.6 | 100.00 % |
| <u>52</u> | OutputZ_leak_vbt1 p51 19.g149 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00497426 uA | 0.00954903 uA | 523.6 | 349.2 | 100.00 % |
| <u>53</u> | OutputZ_leak_vbt1 p52 19.e137 | P | –10 uA | 20 uA | Samples | 5 | 0 | 0.00321628 uA | 0.0189165 uA | 264.3 | 176.3 | 100.00 % |
| <u>54</u> | OutputZ_leak_vbt1 p53 19.e135 | P | -10 uA | 20 uA | Samples | 5 | 0 | -0.000609373 uA | 0.00354832 uA | 1409.1 | 939.4 | 100.00 % |
| <u>55</u> | OutputZ_leak_vbt1 p60 19.g130 | P | –10 uA | 20 uA | Samples | 5 | 0 | 0.00566289 uA | 0.0096586 uA | 517.7 | 345.3 | 100.00 % |
| <u>56</u> | OutputZ_leak_vbt1 p61 19.g104 | P | –10 uA | 20 uA | Samples | 5 | 0 | 0.00831994 uA | 0.00380119 uA | 1315.4 | 877.6 | 100.00 % |
| <u>57</u> | OutputZ_leak_vbt1 p62 19.g102 | P | –10 uA | 20 uA | Samples | 5 | 0 | 0.0118622 uA | 0.00919318 uA | 543.9 | 363.0 | 100.00 % |
| <u>58</u> | OutputZ_leak_vbt1 p63 19.e102 | P | −10 uA | 20 uA | Samples | 5 | 0 | 0.00526151 uA | 0.0113436 uA | 440.8 | 294.0 | 100.00 % |
| <u>59</u> | OutputZ_leak_vbt1 p70 19.g139 | P | –10 uA | 20 uA | Samples | 5 | 0 | 0.00221124 uA | 0.00923536 uA | 541.4 | 361.0 | 100.00 % |
| <u>60</u> | OutputZ_leak_vbt1 p71 19.g147 | P | −10 uA | 20 uA | Samples | 5 | 0 | 0.000996936 uA | 0.00445843 uA | 1121.5 | 747.7 | 100.00 % |
| | | | | | | | | | | | | |
| <u>61</u> | OutputZ_leak_vbt1 p72 19.e104 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.00274427 uA | 0.00883411 uA | 566.0 | 377.4 | 100.00 % |
| <u>62</u> | OutputZ_leak_vbt1 p73 19.e108 | P | -10 uA | 20 uA | Samples | 5 | 0 | 0.0124248 uA | 0.0107394 uA | 465.6 | 310.8 | 100.00 % |
| 62 63 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 | P F | −10 uA n/a . | 20 uA n/a . | Samples Samples | 5 5 | 0 0 | 0.0124248 uA n/a . | 0.0107394 uA n/a . | 465.6 n/a . | 310.8 n/a . | 100.00 % 100.00 % |
| 62 63 Test | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name | Р F Туре | –10 uA n/a . Low L. | 20 uA n/a . High L. | Samples Samples Source | 5 5 Execs | 0 0 Fails | 0.0124248 uA n/a . Mean | 0.0107394 uA n/a . Sigma | 465.6 n/a . Cp | 310.8 n/a . Cpk | 100.00 % 100.00 % Yield |
| 62 63 Test 64 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static | P F Type P | -10 uA n/a . Low L. 10 uA | 20 uA n/a . High L. 500 uA | Samples Samples Source Samples | 5 5 Execs 5 | 0 0 Fails 0 | 0.0124248 uA n/a . Mean 21.4136 uA | 0.0107394 uA n/a . Sigma 0.372153 uA | 465.6 n/a . Cp 219.4 | 310.8 n/a . Cpk 10.22 | 100.00 % 100.00 % Yield 100.00 % |
| 62 63 Test 64 65 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic | P F Type P P | -10 uA n/a . Low L. 10 uA 10 uA | 20 uA n/a . High L. 500 uA | Samples Source Samples Samples | 5 5 Execs 5 5 | 0 0 Fails 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA | 465.6 n/a. Cp 219.4 413.3 | 310.8 n/a . Cpk 10.22 18.21 | 100.00 % 100.00 % Yield 100.00 % 100.00 % |
| 62 63 Test 64 65 67 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 | P F Type P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . | 20 uA n/a . High L. 500 uA 500 uA n/a . | Samples Source Samples Samples Samples Samples | 5 5 Execs 5 5 5 | 0 0 Fails 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 | 465.6 n/a. Cp 219.4 413.3 n/a. | 310.8 n/a . Cpk 10.22 18.21 n/a . | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T5 p50 19.e128 | P F Type P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . | 20 uA n/a . High L. 500 uA 500 uA n/a . n/a . | Samples Samples Source Samples Samples Samples Samples Samples | 5 5 Execs 5 5 5 5 | 0 0 Fails 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 | 465.6 n/a . Cp 219.4 413.3 n/a . n/a . | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 | P F Type P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns | 20 uA n/a . High L. 500 uA 500 uA n/a . n/a . 350 ns | Samples Samples Source Samples Samples Samples Samples Samples Samples | 5 5 Execs 5 5 5 5 5 | 0 0 Fails 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 | P F Type P P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns 150 ns | 20 uA n/a . High L. 500 uA 500 uA n/a . n/a . 350 ns 350 ns | Samples Samples Source Samples Samples Samples Samples Samples Samples Samples | 5 5 Execs 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns | 465.6 n/a . Cp 219.4 413.3 n/a . n/a . 12.78 30.43 | 310.8 n/a . Cpk 10.22 18.21 n/a . n/a . 11.04 28.85 | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 | P F Type P P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns 150 ns | 20 uA n/a . High L. 500 uA 500 uA n/a . n/a . 350 ns 350 ns 100 ns | Samples | 5 5 Execs 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns | 465.6 n/a . Cp 219.4 413.3 n/a . n/a . 12.78 30.43 6.33 | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 | P F Type P P P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns 150 ns 1 ns n/a . | 20 uA n/a . High L. 500 uA 500 uA n/a . n/a . 350 ns 350 ns 100 ns n/a . | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns | 465.6 n/a . Cp 219.4 413.3 n/a . n/a . 12.78 30.43 6.33 n/a . | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 | P F Type P P P P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns 150 ns 1 ns n/a . n/a . | 20 uA n/a . High L. 500 uA 500 uA n/a . n/a . 350 ns 350 ns 100 ns n/a . n/a . | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 | 465.6 n/a . Cp 219.4 413.3 n/a . n/a . 12.78 30.43 6.33 n/a . n/a . | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 n/a. n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p50 19.e135 Functional_T8 p53 19.e135 | P F Type P P P P P P P | -10 uA n/a. Low L. 10 uA 10 uA n/a. n/a. 150 ns 1 ns n/a. n/a. 150 ns | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. n/a. 350 ns | Samples Samples Source Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 | 310.8 n/a. Cpk 10.22 18.21 n/a. 11.04 28.85 0.9459 n/a. n/a. 0.3651 | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 76 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 p53 19.e135 | P F Type P P P P P P P | -10 uA n/a . Low L. 10 uA 10 uA 10 uA 150 ns 150 ns 1 ns n/a . n/a . 150 ns | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. n/a. 350 ns | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns 217.2 ns | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns 37.7518 ns | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 0.8830 | 310.8 n/a. Cpk 10.22 18.21 n/a. 11.04 28.85 0.9459 n/a. n/a. 0.3651 0.5933 | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 76 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p50 19.e125 Functional_T7 p53 19.e135 Functional_T8 p53 19.e135 | P F Type P P P P P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns 150 ns 1 ns n/a . n/a . 150 ns | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. 350 ns 350 ns | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns 217.2 ns | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns 37.7518 ns 2709.64 ns | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 0.8830 0.0061 | 310.8 n/a. Cpk 10.22 18.21 n/a. 11.04 28.85 0.9459 n/a. n/a. 0.3651 0.5933 -0.2151 | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 76 77 78 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 A8 0 Soft_Bin parameter | P F Type P P P P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns 150 ns 1 ns n/a . 150 ns 150 ns | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. 350 ns 350 ns | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns 217.2 ns 1848.8 ns | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns 37.7518 ns 2709.64 ns | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 0.8830 0.0061 n/a. | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 n/a. n/a. 0.3651 0.5933 -0.2151 n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 76 77 78 786000 786001 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 A8 0 Soft_Bin parameter Hard_Bin parameter | P F Type P P P P P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns 150 ns 1 ns n/a . 150 ns 150 ns 1 ns n/a . n/a . | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. 350 ns 350 ns 100 ns n/a. n/a. | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns 217.2 ns 1848.8 ns | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns 37.7518 ns 2709.64 ns 0 0 | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 0.8830 0.0061 n/a. n/a. | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 n/a. n/a. 0.3651 0.5933 -0.2151 n/a. n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 76 77 78 786000 786001 786002 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 A8 0 Soft_Bin parameter Hard_Bin parameter Die_X parameter | P F Type P P P P P P P P | -10 uA n/a . Low L. 10 uA 10 uA n/a . n/a . 150 ns 150 ns 1 ns n/a . 150 ns 150 ns 1 ns n/a . n/a . 150 ns | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. 350 ns 350 ns 100 ns n/a. n/a. 350 ns | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 Fails 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns 217.2 ns 1848.8 ns 1 0.4 | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns 37.7518 ns 2709.64 ns 0 0 0.547723 | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 0.8830 0.0061 n/a. n/a. n/a. | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 n/a. 0.3651 0.5933 -0.2151 n/a. n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 76 77 78 786000 786001 786002 786003 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 A8 0 Soft_Bin parameter Hard_Bin parameter Die_X parameter Die_Y parameter | P F Type P P P P P P P P | -10 uA n/a. Low L. 10 uA 10 uA n/a. n/a. 150 ns 150 ns 1 ns n/a. 150 ns 1 ns n/a. n/a. 150 ns | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. 350 ns 350 ns 100 ns n/a. n/a. 350 ns | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 0 Fails 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns 217.2 ns 1848.8 ns 1 0.4 1.2 | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns 37.7518 ns 2709.64 ns 0 0.547723 0.83666 | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 0.8830 0.0061 n/a. n/a. n/a. | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 n/a. 0.3651 0.5933 -0.2151 n/a. n/a. n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 76 77 78 786000 786001 786002 786003 786004 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p50 19.e128 Functional_T7 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 A8 0 Soft_Bin parameter Hard_Bin parameter Die_X parameter Die_Y parameter Test_Time parameter | P F Type P P P P P P P P | -10 uA n/a. Low L. 10 uA 10 uA n/a. n/a. 150 ns 150 ns 1 ns n/a. 150 ns 1 ns n/a. n/a. 150 ns 1 ns n/a. 0.0 sec | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. 350 ns 350 ns 100 ns n/a. n/a. 340 ns 100 ns n/a. n/a. n/a. n/a. n/a. n/a. | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 0 Fails 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns 217.2 ns 1848.8 ns 1 0.4 1.2 2.0294 sec | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns 37.7518 ns 2709.64 ns 0 0 0.547723 0.83666 0.877026 sec | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 0.8830 0.0061 n/a. n/a. n/a. n/a. | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 n/a. 0.3651 0.5933 -0.2151 n/a. n/a. n/a. 0.7713 | 100.00 % 100.00 % Yield 100.00 % |
| 62 63 Test 64 65 67 68 70 71 72 73 74 76 77 78 786000 786001 786002 786003 | OutputZ_leak_vbt1 p73 19.e108 Functional_T4 Name icc_static_vbt11 vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_static Icc_dynamic vcc 15.e201 <> Icc_dynamic Functional_T5 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 p50 19.e128 Functional_T6 A8 0 Functional_T7 p50 19.e128 Functional_T7 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 p53 19.e135 Functional_T8 A8 0 Soft_Bin parameter Hard_Bin parameter Die_X parameter Die_Y parameter | P F Type P P P P P P P P | -10 uA n/a. Low L. 10 uA 10 uA n/a. n/a. 150 ns 150 ns 1 ns n/a. 150 ns 1 ns n/a. n/a. 150 ns | 20 uA n/a. High L. 500 uA 500 uA 500 uA n/a. n/a. 350 ns 350 ns 100 ns n/a. 350 ns 350 ns 100 ns n/a. n/a. 350 ns | Samples | 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 | 0 0 0 Fails 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 | 0.0124248 uA n/a . Mean 21.4136 uA 20.7956 uA 0.1442 3.284 236.4 ns 244.8 ns 8.4 ns 2.9 0.1378 278.4 ns 217.2 ns 1848.8 ns 1 0.4 1.2 | 0.0107394 uA n/a . Sigma 0.372153 uA 0.197597 uA 0.00342053 0.00244951 2.60768 ns 1.09545 ns 2.60768 ns 0 0.00228035 65.3667 ns 37.7518 ns 2709.64 ns 0 0.547723 0.83666 | 465.6 n/a. Cp 219.4 413.3 n/a. n/a. 12.78 30.43 6.33 n/a. n/a. 0.5099 0.8830 0.0061 n/a. n/a. n/a. | 310.8 n/a. Cpk 10.22 18.21 n/a. n/a. 11.04 28.85 0.9459 n/a. 0.3651 0.5933 -0.2151 n/a. n/a. n/a. | 100.00 % 100.00 % Yield 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % 100.00 % |

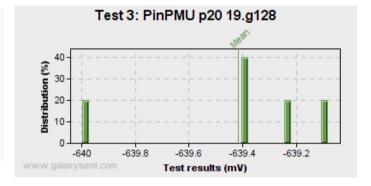
Tests Statistics 3/55



Name PinPMU p20 19.g128

Test type Parametric Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -639.417 mV Sigma 0.348026 mV 0.915706 mV Range Cp / Cpk 526.8 / 516.6

Samples

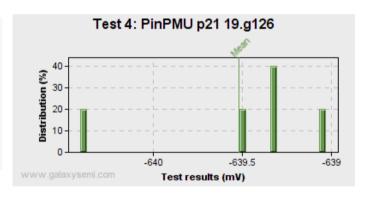


Test

Name PinPMU p21 19.g126

Test type Parametric Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -639.519 mV Sigma 0.522085 mV Range 1.37371 mV Cp / Cpk 351.2 / 344.5

Samples 5

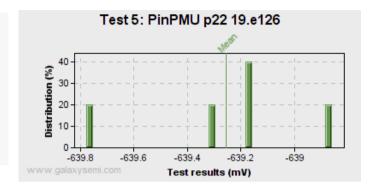


Histogram of Tests 4/55

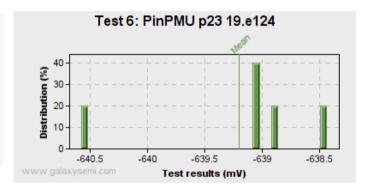
Test <u>5</u> Name Pinl

Name PinPMU p22 19.e126

Test type Parametric Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -639.257 mV Sigma 0.334326 mV Range 0.915587 mV Cp / Cpk 548.4 / 537.7 Samples



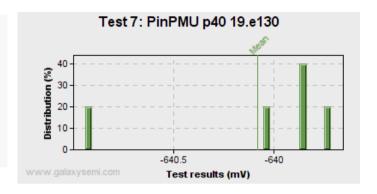
| Test | <u>6</u> |
|--------------|--------------------|
| Name | PinPMU p23 19.e124 |
| Test type | Parametric |
| Low limit | -1200 mV |
| High limit | -100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -639.195 mV |
| Sigma | 0.807619 mV |
| Range | 2.13677 mV |
| Cp / Cpk | 227.0 / 222.5 |
| Samples | 5 |

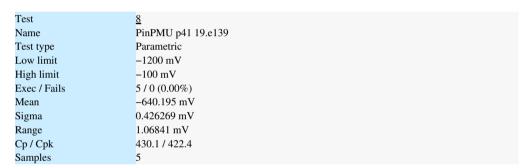


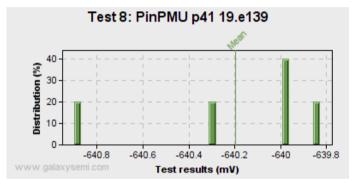
Histogram of Tests 5/55

Name PinPMU p40 19.e130

Test type Parametric Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -640.081 mV Sigma 0.48976 mV Range 1.22082 mV Cp / Cpk 374.3 / 367.6 Samples 5







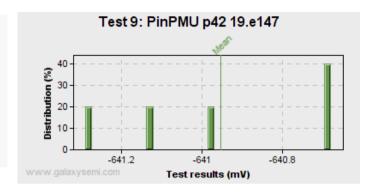
Histogram of Tests 6/55

Test Name

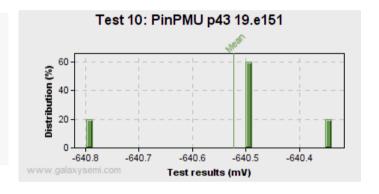
9 PinPMU p42 19.e147

Test type Parametric Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -640.953 mV Sigma 0.272958 mV Range 0.610352 mV Cp / Cpk 671.7 / 660.6

Samples



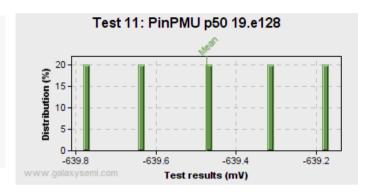
| Test | <u>10</u> |
|--------------|--------------------|
| Name | PinPMU p43 19.e151 |
| Test type | Parametric |
| Low limit | -1200 mV |
| High limit | -100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -640.523 mV |
| Sigma | 0.167282 mV |
| Range | 0.458121 mV |
| Cp / Cpk | 1096.0 / 1077.1 |
| Samples | 5 |



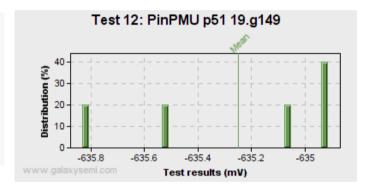
Histogram of Tests 7/55

11 PinPMU p50 19.e128 Name

Parametric Test type Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -639.475 mV Sigma 0.241413 mV Range 0.610709 mV Cp / Cpk 759.4 / 744.9 Samples



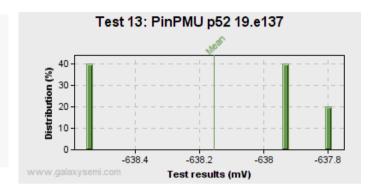
| Test | <u>12</u> |
|--------------|--------------------|
| Name | PinPMU p51 19.g149 |
| Test type | Parametric |
| Low limit | −1200 mV |
| High limit | -100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -635.25 mV |
| Sigma | 0.409467 mV |
| Range | 0.915587 mV |
| Cp / Cpk | 447.7 / 435.7 |
| Samples | 5 |



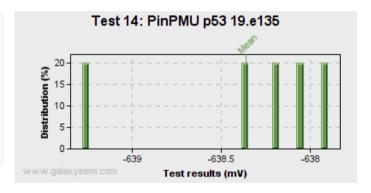
Histogram of Tests 8/55

13 PinPMU p52 19.e137 Name

Parametric Test type Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -638.154 mV Sigma 0.367656 mV Range 0.763297 mV Cp / Cpk 498.7 / 487.9 Samples 5



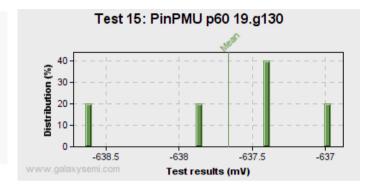
| Test | <u>14</u> |
|--------------|--------------------|
| Name | PinPMU p53 19.e135 |
| Test type | Parametric |
| Low limit | -1200 mV |
| High limit | -100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -638.36 mV |
| Sigma | 0.539505 mV |
| Range | 1.37335 mV |
| Cp / Cpk | 339.8 / 332.6 |
| Samples | 5 |



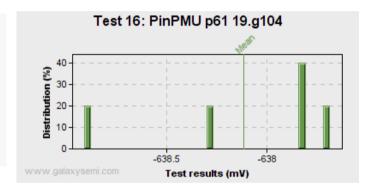
Histogram of Tests 9/55

15 PinPMU p60 19.g130 Name

Parametric Test type Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -637.663 mV Sigma 0.634843 mV Range 1.67894 mV Cp / Cpk 288.8 / 282.3 Samples 5



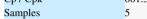
| Test | <u>16</u> |
|--------------|--------------------|
| Name | PinPMU p61 19.g104 |
| Test type | Parametric |
| Low limit | −1200 mV |
| High limit | –100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -638.113 mV |
| Sigma | 0.499234 mV |
| Range | 1.22094 mV |
| Cp / Cpk | 367.2 / 359.3 |
| Samples | 5 |

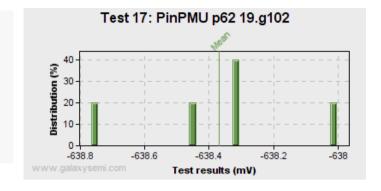


Histogram of Tests 10/55

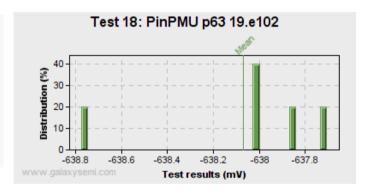
17 PinPMU p62 19.g102 Name

Parametric Test type Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -638.369 mV Sigma 0.277231 mV Range 0.763059 mV Cp / Cpk 661.3 / 647.3





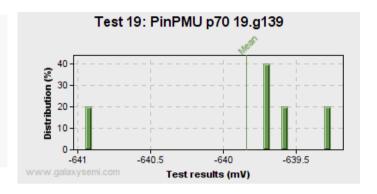
| Test | <u>18</u> |
|--------------|--------------------|
| Name | PinPMU p63 19.e102 |
| Test type | Parametric |
| Low limit | -1200 mV |
| High limit | −100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -638.071 mV |
| Sigma | 0.41227 mV |
| Range | 1.06812 mV |
| Cp / Cpk | 444.7 / 435.0 |
| Samples | 5 |



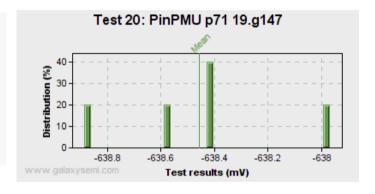
Histogram of Tests 11/55

19 PinPMU p70 19.g139 Name

Parametric Test type Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -639.844 mV Sigma 0.642248 mV Range 1.67924 mV Cp / Cpk 285.5 / 280.2 Samples 5



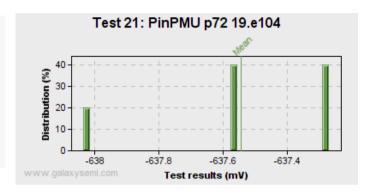
| Test | <u>20</u> |
|--------------|--------------------|
| Name | PinPMU p71 19.g147 |
| Test type | Parametric |
| Low limit | –1200 mV |
| High limit | –100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -638.457 mV |
| Sigma | 0.33091 mV |
| Range | 0.915825 mV |
| Cp / Cpk | 554.0 / 542.4 |
| Samples | 5 |



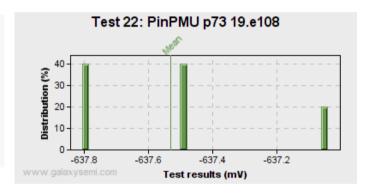
Histogram of Tests 12/55

21 PinPMU p72 19.e104 Name

Test type Parametric Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -637.545 mV Sigma 0.312858 mV Range 0.763297 mV Cp / Cpk 586.0 / 572.7 Samples



| Test | <u>22</u> |
|--------------|--------------------|
| Name | PinPMU p73 19.e108 |
| Test type | Parametric |
| Low limit | -1200 mV |
| High limit | -100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -637.529 mV |
| Sigma | 0.312762 mV |
| Range | 0.763059 mV |
| Cp / Cpk | 586.2 / 572.9 |
| Samples | 5 |

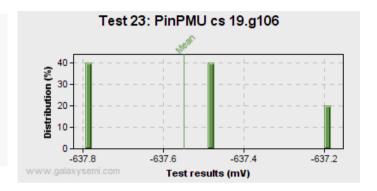


Histogram of Tests 13/55

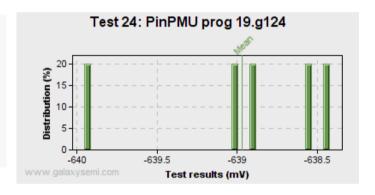
23 PinPMU cs 19.g106 Name

Parametric Test type Low limit -1200 mV High limit -100 mV Exec / Fails 5 / 0 (0.00%) Mean -637.549 mV Sigma 0.255428 mV Range 0.61059 mV Cp / Cpk 717.7 / 701.5

Samples



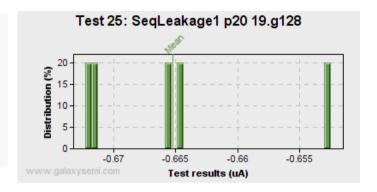
| Test | <u>24</u> |
|--------------|---------------------|
| Name | PinPMU prog 19.g124 |
| Test type | Parametric |
| Low limit | -1200 mV |
| High limit | -100 mV |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | -638.972 mV |
| Sigma | 0.596923 mV |
| Range | 1.52606 mV |
| Cp / Cpk | 307.1 / 301.0 |
| Samples | 5 |



Histogram of Tests 14/55

SeqLeakage1 p20 19.g128 Name

Test type Parametric Low limit -30 uA High limit 10 uA Exec / Fails 5 / 0 (0.00%) Mean -0.665264 uA Sigma 0.00794774 uA Range 0.0198199 uA Cp / Cpk 838.8 / 447.3 Samples 5

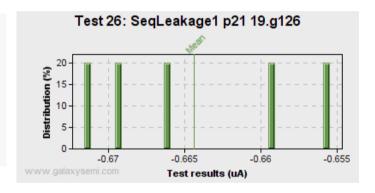


Test 26

SeqLeakage1 p21 19.g126 Name

Test type Parametric -30 uA Low limit High limit 10 uA Exec / Fails 5 / 0 (0.00%) Mean -0.664335 uA Sigma 0.00677483 uA Range 0.0160782 uA Cp / Cpk 984.0 / 524.7

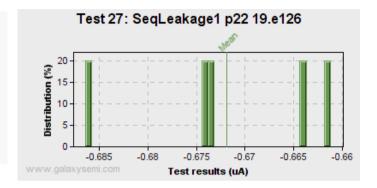
Samples



Histogram of Tests 15/55

Name SeqLeakage1 p22 19.e126

Test type Parametric Low limit -30 uA High limit 10 uA Exec / Fails 5 / 0 (0.00%) Mean -0.671868 uA Sigma 0.00990592 uA Range 0.0252581 uA Cp / Cpk 673.0 / 359.1 Samples 5

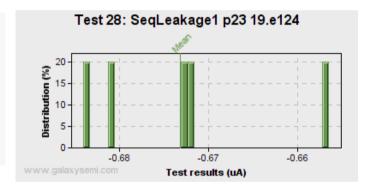




SeqLeakage1 p23 19.e124 Name

Test type Parametric -30 uA Low limit High limit 10 uA Exec / Fails 5 / 0 (0.00%) Mean -0.673144 uA Sigma 0.0106867 uA Range 0.0274659 uA Cp / Cpk 623.8 / 332.9 5

Samples

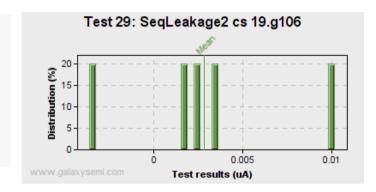


Histogram of Tests 16/55

29 SeqLeakage2 cs 19.g106 Name

Test type Parametric Low limit -30 uA High limit 10 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00283109 uA Sigma 0.00491731 uA Range 0.0137729 uA Cp / Cpk 1355.8 / 677.7

Samples 5

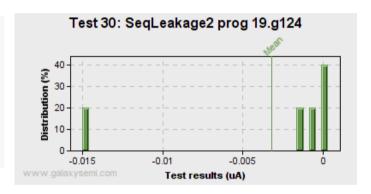




SeqLeakage2 prog 19.g124 Name

Test type Parametric -30 uA Low limit High limit 10 uA Exec / Fails 5 / 0 (0.00%) Mean -0.00320883 uA Sigma 0.00660766 uA 0.0152801 uA Range Cp / Cpk 1008.9 / 504.6

Samples 5

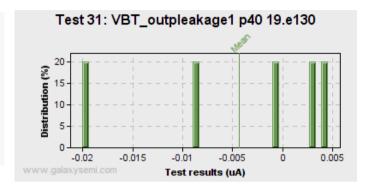


Histogram of Tests 17/55

Name VBT_outpleakage1 p40 19.e130

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.00436721 uA Sigma 0.0100862 uA Range 0.0245176 uA Cp / Cpk 495.7 / 330.3

Samples 5

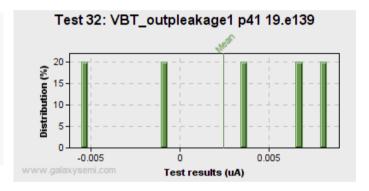


Test 32

Name VBT_outpleakage1 p41 19.e139

Test type Parametric -10 uA Low limit High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00244967 uA Sigma 0.00566692 uA Range 0.0137794 uA Cp / Cpk 882.3 / 588.4

Samples 5

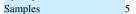


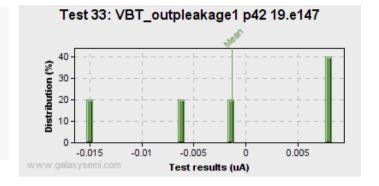
Histogram of Tests 18/55

Test <u>33</u>

Name VBT_outpleakage1 p42 19.e147

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.00129372 uA Sigma 0.0100471 uA Range 0.0235913 uA Cp / Cpk 497.7 / 331.7



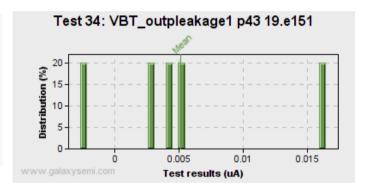


Test 34 Name VB

VBT_outpleakage1 p43 19.e151

Test type Parametric -10 uA Low limit High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00512209 uA Sigma 0.00699416 uA Range 0.0191123 uA Cp / Cpk 714.9 / 476.8

Samples 5



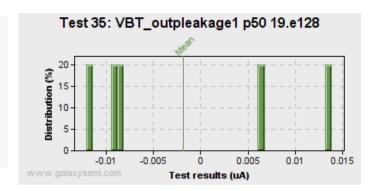
Histogram of Tests 19/55

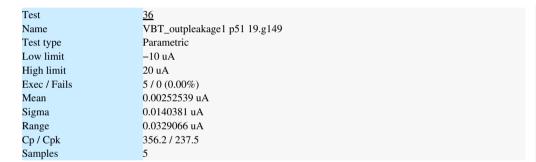
Test <u>35</u>

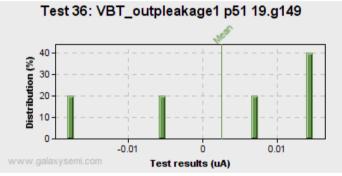
Name VBT_outpleakage1 p50 19.e128

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.00182717 uA Sigma 0.0112614 uA Range 0.025885 uA Cp / Cpk 444.0 / 295.9

Samples 5







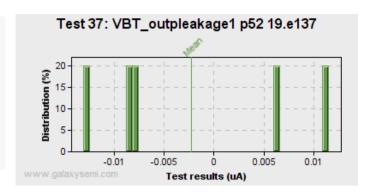
Histogram of Tests 20/55

Test <u>37</u>

Name VBT_outpleakage1 p52 19.e137

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.00229734 uA Sigma 0.0105138 uA Range 0.024505 uA Cp / Cpk 475.6 / 317.0

Samples 5

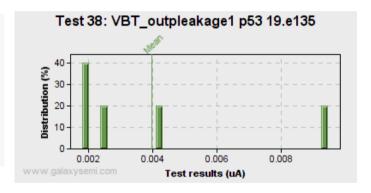


| Test | <u>38</u> |
|------|-----------|
| | T 7T |

Name VBT_outpleakage1 p53 19.e135

Test type Parametric -10 uA Low limit High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00396093 uA Sigma 0.00320465 uA Range 0.00761717 uA Cp / Cpk 1560.2 / 1040.6

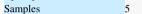
Samples 5

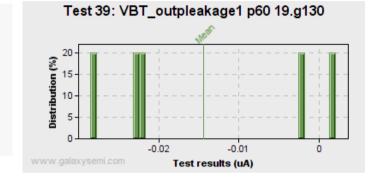


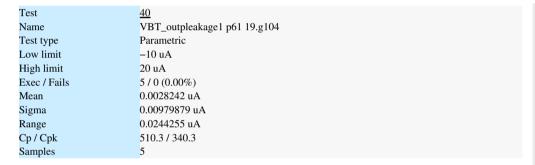
Histogram of Tests 21/55

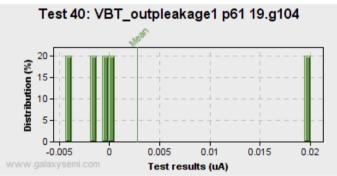
Name VBT_outpleakage1 p60 19.g130

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.0143868 uA Sigma 0.0136743 uA Range 0.0306102 uA Cp / Cpk 365.6 / 243.4









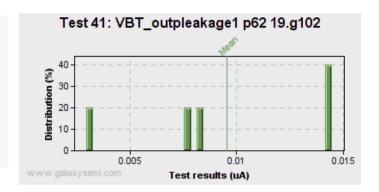
Histogram of Tests 22/55

Test <u>41</u>

Name VBT_outpleakage1 p62 19.g102

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00956627 uA Sigma 0.00491822 uA Range 0.0114795 uA Cp / Cpk 1016.6 / 678.4

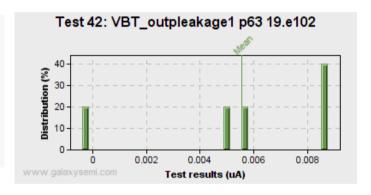
Samples 5





Low limit -10 uA
High limit 20 uA
Exec / Fails 5 / 0 (0.00%)
Mean 0.00556653 uA
Sigma 0.00375119 uA
Range 0.00915045 uA
Cp / Cpk 1332.9 / 889.1

Samples 5

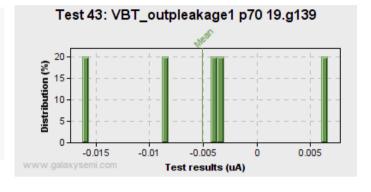


Histogram of Tests 23/55

Name VBT_outpleakage1 p70 19.g139

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.00510874 uA Sigma 0.00834578 uA Range 0.0228749 uA Cp / Cpk 599.1 / 399.2

Samples 5

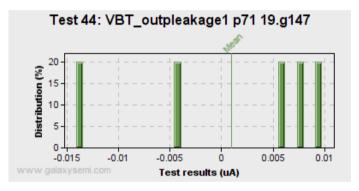


Test 44

Name VBT_outpleakage1 p71 19.g147

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.000996936 uA Sigma 0.00991909 uA Range 0.0237731 uA Cp / Cpk 504.1 / 336.1

Samples 5

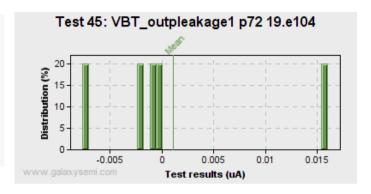


Histogram of Tests 24/55

Name VBT_outpleakage1 p72 19.e104

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00106722 uA Sigma 0.00886694 uA Range 0.0236312 uA Cp / Cpk 563.9 / 376.0

Samples 5

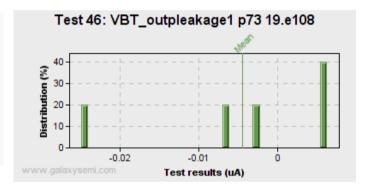




VBT_outpleakage1 p73 19.e108 Name

Test type Parametric -10 uA Low limit High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.00449732 uA Sigma 0.0126796 uA Range 0.0312525 uA Cp / Cpk 394.3 / 262.8

Samples

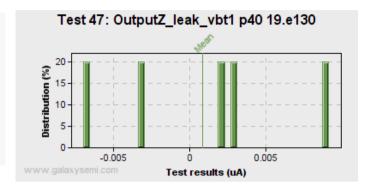


Histogram of Tests 25/55

Name OutputZ_leak_vbt1 p40 19.e130

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.000842794 uA Sigma 0.00616284 uA Range 0.0160897 uA Cp / Cpk 811.3 / 540.9

Samples 5

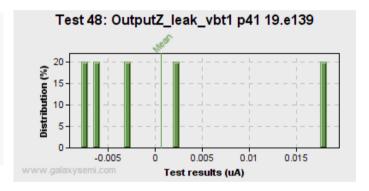


Test <u>48</u>

Name OutputZ_leak_vbt1 p41 19.e139

Test type Parametric -10 uA Low limit High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.000612416 uA Sigma 0.010552 uA 0.0260277 uA Range Cp / Cpk 473.8 / 315.9

Samples 5

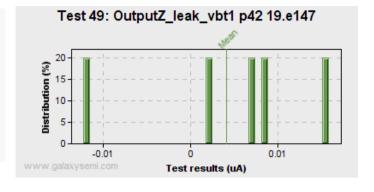


Histogram of Tests 26/55

Name OutputZ_leak_vbt1 p42 19.e147

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00418555 uA Sigma 0.0104289 uA Range 0.0281574 uA Cp / Cpk 479.4 / 319.8

Samples 5

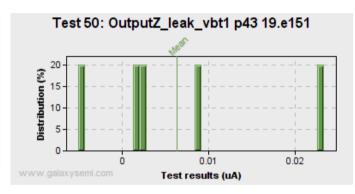




OutputZ_leak_vbt1 p43 19.e151 Name

Test type Parametric -10 uA Low limit High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00634528 uA Sigma 0.0106673 uA Range 0.0282862 uA Cp / Cpk 468.7 / 312.7

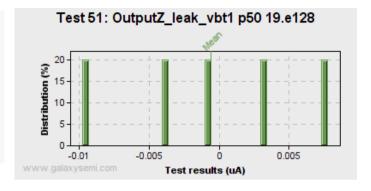
Samples



Histogram of Tests 27/55

Name OutputZ_leak_vbt1 p50 19.e128

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.000609058 uA Sigma 0.00665885 uA Range 0.0175104 uA Cp / Cpk 750.9 / 500.6 Samples



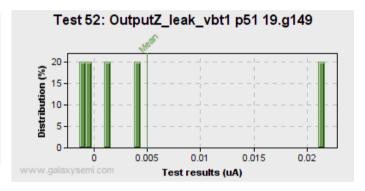


OutputZ_leak_vbt1 p51 19.g149 Name

5

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00497426 uA Sigma 0.00954903 uA Range 0.0229581 uA Cp / Cpk 523.6 / 349.2

Samples

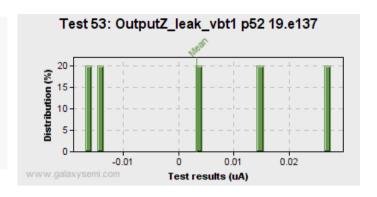


Histogram of Tests 28/55

Name OutputZ_leak_vbt1 p52 19.e137

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00321628 uA Sigma 0.0189165 uA Range 0.0444153 uA Cp / Cpk 264.3 / 176.3

Samples 5

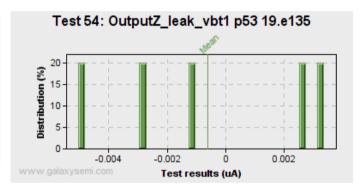


Test <u>54</u>

Name OutputZ_leak_vbt1 p53 19.e135

Test type Parametric -10 uA Low limit High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean -0.000609373 uA Sigma 0.00354832 uA Range 0.00837888 uA Cp / Cpk 1409.1 / 939.4

Samples 5

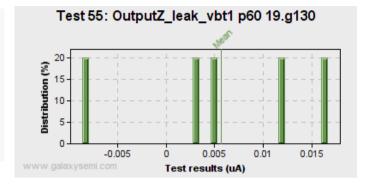


Histogram of Tests 29/55

Test <u>55</u>

Name OutputZ_leak_vbt1 p60 19.g130

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00566289 uA Sigma 0.0096586 uA Range 0.0252534 uA Cp / Cpk 517.7 / 345.3 Samples 5

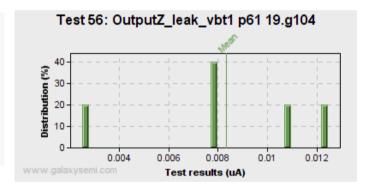


Test <u>56</u>

Name OutputZ_leak_vbt1 p61 19.g104

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00831994 uA Sigma 0.00380119 uA Range 0.00992286 uA Cp / Cpk 1315.4 / 877.6

Samples 5



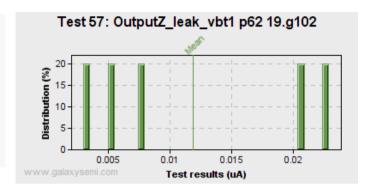
Histogram of Tests 30/55

Test <u>57</u>

Name OutputZ_leak_vbt1 p62 19.g102

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.0118622 uA Sigma 0.00919318 uA Range 0.0198978 uA Cp / Cpk 543.9 / 363.0

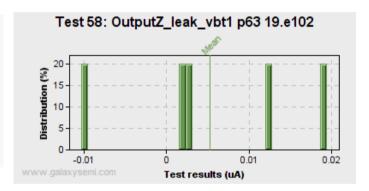
Samples 5





Name OutputZ_leak_vbt1 p63 19.e102

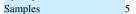
Test type Parametric -10 uA Low limit High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00526151 uA Sigma 0.0113436 uA 0.029739 uA Range Cp / Cpk 440.8 / 294.0 Samples

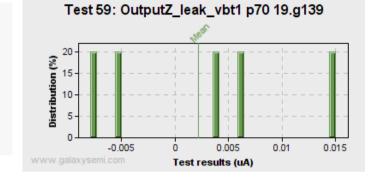


Histogram of Tests 31/55

Name OutputZ_leak_vbt1 p70 19.g139

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00221124 uA Sigma 0.00923536 uA Range 0.0228749 uA Cp / Cpk 541.4 / 361.0



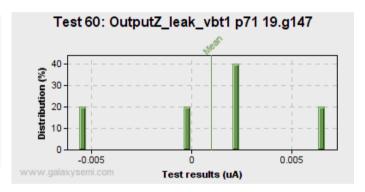


Test <u>60</u>

Name OutputZ_leak_vbt1 p71 19.g147

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.000996936 uA Sigma 0.00445843 uA Range 0.01227 uA Cp / Cpk 1121.5 / 747.7

Samples 5



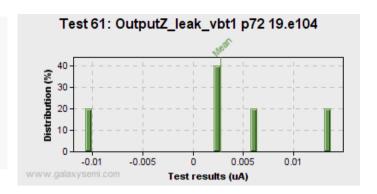
Histogram of Tests 32/55

Test <u>61</u>

Name OutputZ_leak_vbt1 p72 19.e104

Test type Parametric Low limit -10 uA High limit 20 uA Exec / Fails 5 / 0 (0.00%) Mean 0.00274427 uA Sigma 0.00883411 uA Range 0.0243935 uA Cp / Cpk 566.0 / 377.4

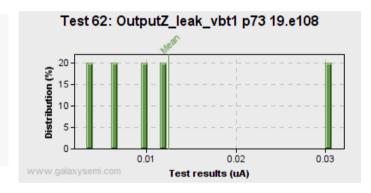
Samples 5





Low limit -10 uA
High limit 20 uA
Exec / Fails 5 / 0 (0.00%)
Mean 0.0124248 uA
Sigma 0.0107394 uA
Range 0.0274413 uA
Cp / Cpk 465.6 / 310.8

Samples 5



Histogram of Tests 33/55

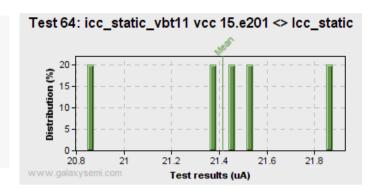
Test <u>64</u>

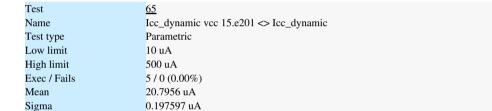
Name icc_static_vbt11 vcc 15.e201 <> Icc_static

0.429154 uA

Test type Parametric Low limit 10 uA High limit 500 uA Exec / Fails 5 / 0 (0.00%) Mean 21.4136 uA Sigma 0.372153 uA Range 1.02997 uA Cp / Cpk 219.4 / 10.22

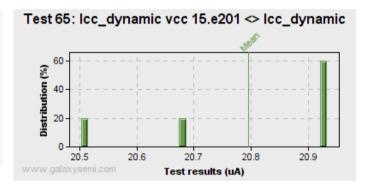
Samples 5





Cp / Cpk 413.3 / 18.21 Samples 5

Range



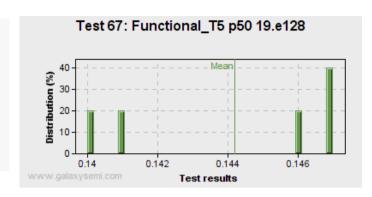
Histogram of Tests 34/55

Functional_T5 p50 19.e128 Name

Test type Parametric Low limit n/a . High limit n/a .

Exec / Fails 5 / 0 (0.00%) Mean 0.1442 Sigma 0.00342053 Range 0.007 Cp / Cpk n/a . / n/a .

Samples 5

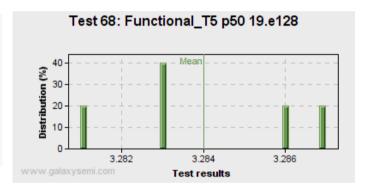




Functional_T5 p50 19.e128 Name

Test type Parametric Low limit n/a . High limit n/a .

Exec / Fails 5 / 0 (0.00%) Mean 3.284 Sigma 0.00244951 0.00600004 Range Cp / Cpk n/a . / n/a . Samples

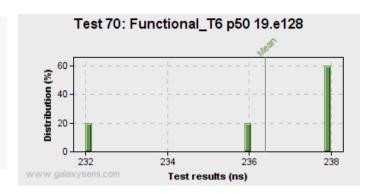


Histogram of Tests 35/55 Test <u>70</u>

Name Functional_T6 p50 19.e128

Test type Parametric Low limit 150 ns High limit 350 ns Exec / Fails 5 / 0 (0.00%) Mean 236.4 ns Sigma 2.60768 ns Range 5.99999 ns Cp / Cpk 12.78 / 11.04

Samples 5

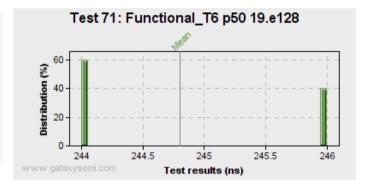


Test <u>71</u>

Name Functional_T6 p50 19.e128

Test type Parametric Low limit 150 ns High limit 350 ns Exec / Fails 5 / 0 (0.00%) Mean 244.8 ns Sigma 1.09545 ns 2.00001 ns Range Cp / Cpk 30.43 / 28.85

Samples 5



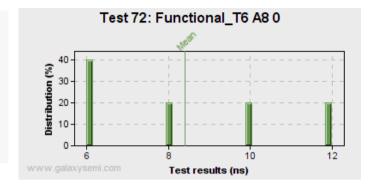
Histogram of Tests 36/55

Test <u>72</u>

Name Functional_T6 A8 0

Test type Parametric Low limit 1 ns 100 ns High limit 5 / 0 (0.00%) Exec / Fails Mean 8.4 ns Sigma 2.60768 ns Range 6 ns Cp / Cpk 6.33 / 0.9459

Samples 5



Test 73

Name Functional_T7 p50 19.e128

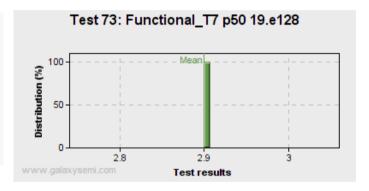
Test type Parametric
Low limit n/a .
High limit n/a .

Exec / Fails 5 / 0 (0.00%)

Mean 2.9
Sigma 0
Range 0

Cp / Cpk n/a . / n/a .

Samples 5



Histogram of Tests 37/55

Test 74

Name Functional_T7 p53 19.e135

Test type Parametric Low limit n/a.
High limit n/a.

Exec / Fails 5 / 0 (0.00%)

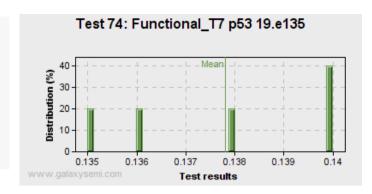
Mean 0.1378

Sigma 0.00228035

Range 0.005

Cp / Cpk n/a . / n/a .

Samples 5

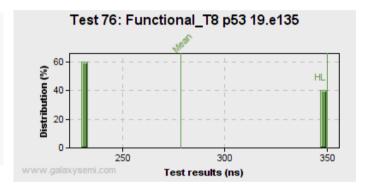




Name Functional_T8 p53 19.e135

Test type Parametric Low limit 150 ns High limit 350 ns Exec / Fails 5 / 0 (0.00%) Mean 278.4 ns Sigma 65.3667 ns Range 120 ns Cp / Cpk 0.5099 / 0.3651

Samples 5



Histogram of Tests 38/55

Test 77

Name Functional_T8 p53 19.e135

 Test type
 Parametric

 Low limit
 150 ns

 High limit
 350 ns

 Exec / Fails
 5 / 0 (0.00%)

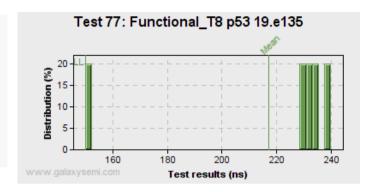
 Mean
 217.2 ns

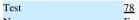
 Sigma
 37.7518 ns

 Range
 90 ns

Cp / Cpk 0.8830 / 0.5933

Samples 5





Name Functional_T8 A8 0

 Test type
 Parametric

 Low limit
 1 ns

 High limit
 100 ns

 Exec / Fails
 5 / 3 (60.00%)

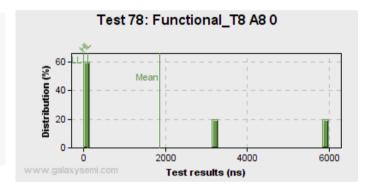
 Mean
 1848.8 ns

 Sigma
 2709.64 ns

 Range
 6000 ns

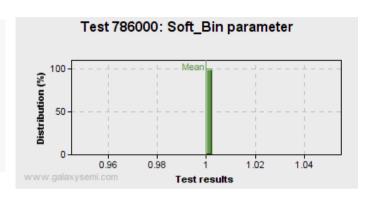
Cp / Cpk 0.0061 / -0.2151=> Warning: Process is over the high limit

Samples 5

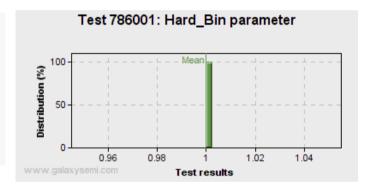


Histogram of Tests 39/55

Test 786000 Name Soft_Bin parameter Test type Low limit n/a . High limit n/a . Exec / Fails 5 / 0 (0.00%) Mean Sigma 0 Range 0 Cp / Cpk n/a . / n/a . Samples



| Test | <u>786001</u> |
|--------------|--------------------|
| Name | Hard_Bin parameter |
| Test type | - |
| Low limit | n/a . |
| High limit | n/a . |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | 1 |
| Sigma | 0 |
| Range | 0 |
| Cp / Cpk | n/a . / n/a . |
| Samples | 5 |



Histogram of Tests 40/55

Test <u>786002</u>

Name Die_X parameter

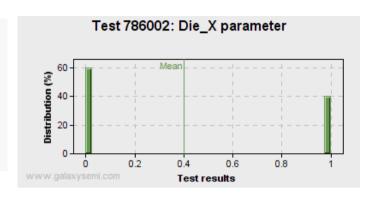
Test type – Low limit n/a. High limit n/a.

Exec / Fails 5 / 0 (0.00%)
Mean 0.4
Sigma 0.547723

Range 1

Cp / Cpk n/a . / n/a .

Samples 5



 Test
 786003

 Name
 Die_Y parameter

 Test type

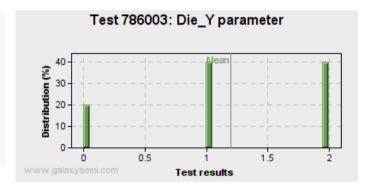
 Low limit
 n/a .

 High limit
 n/a .

Exec / Fails 5 / 0 (0.00%)
Mean 1.2
Sigma 0.83666
Range 2

Cp / Cpk n/a . / n/a .

Samples



Histogram of Tests 41/55

Test <u>786004</u>

Name Test_Time parameter

Test type

Low limit 0.0 sec High limit n/a.

 Exec / Fails
 5 / 0 (0.00%)

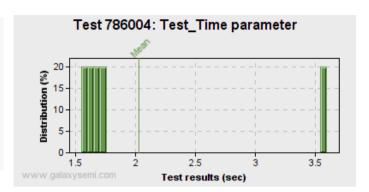
 Mean
 2.0294 sec

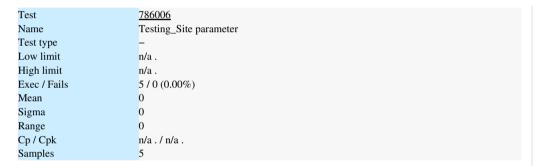
 Sigma
 0.877026 sec

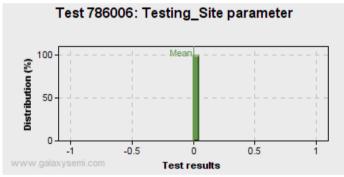
 Range
 2.043 sec

 Cp / Cpk
 n/a . / 0.7713

Samples 5

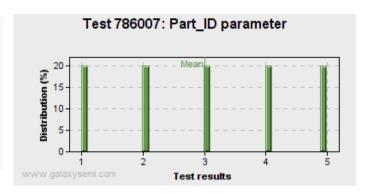






Histogram of Tests 42/55

| Test | <u>786007</u> |
|--------------|-------------------|
| Name | Part_ID parameter |
| Test type | - |
| Low limit | n/a . |
| High limit | n/a . |
| Exec / Fails | 5 / 0 (0.00%) |
| Mean | 3 |
| Sigma | 1.58114 |
| Range | 4 |
| Cp / Cpk | n/a . / n/a . |
| Samples | 5 |





| Test | Name | Ср | Test Cp Chart |
|-----------|---------------------------|--------|---------------|
| <u>78</u> | Functional_T8 A8 0 | 0.0061 | |
| <u>76</u> | Functional_T8 p53 19.e135 | 0.5099 | |
| <u>77</u> | Functional_T8 p53 19.e135 | 0.8830 | |

Shows all Cp <= 1.7 (Defined in Options), section 'Pareto/Define Cp cut-off limit')

Pareto of Tests Cp 43/55



| Test | Name | Cpk | Test Cpk Chart |
|---------------|---------------------------|---------|----------------|
| <u>78</u> | Functional_T8 A8 0 | -0.2151 | |
| <u>76</u> | Functional_T8 p53 19.e135 | 0.3651 | |
| <u>77</u> | Functional_T8 p53 19.e135 | 0.5933 | |
| <u>786004</u> | Test_Time parameter | 0.7713 | |
| <u>72</u> | Functional_T6 A8 0 | 0.9459 | |

Shows all Cpk <= 1.3 (Defined in Options, section 'Pareto/Define Cp cut-off limit')

Pareto of Tests Cpk 44/55



| Test | Name | Failing Bin | Failures count | Yield Loss | Fail contribution | Test Fail rate | Failures Chart |
|-----------|--------------------|----------------|----------------|------------|-------------------|----------------|----------------|
| <u>78</u> | Functional_T8 A8 0 | - | 3 | 60.0 % | n/a | 60.0 % | |
| _ | Cumul. of failures | _ | 3 | 60.0 % | 0.0 % | 60.0 % | |

- -- Yield loss: number of failed test executions / number of parts
- -- Fail contribution: number of failed test executions / number of parts failed
- -- Test Fail rate: number of failed test executions / number of test executions

Pareto of Tests failures 45/55



Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **5**Total patterns detected: **1**

| Fail count | % of failures | % of tested | Functional Failure signatures (tested pins failing together) |
|------------|---------------|-------------|--|
| 3 | 100.00 % | 60.00 % | % Functional_T8 A8 0 (Test 78) |
| 3 | 100 % | | - Total failures detected |

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut-off limit')



Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected



Pareto of Software Bins 47/55



Pareto of Hardware Bins 48/55



Show Software bins

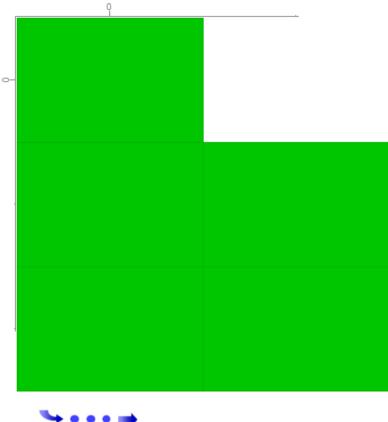
Devices tested (with retests)

5 (only applies to Wafermaps) Total physical parts tested



| Top 10 Software Binning | 1 |
|-------------------------|--------|
| Color | |
| Pass/Fail | P |
| Percentage | 100.0% |
| Total count | 5 |

List of Individual Maps 49/55 Map style STRIP map (parts tested are PACKAGED DEVICES!) Total physical parts 5 tested Parts processed All Data / parts (any Bin) Data from Sites All sites Strip started Tue Sep 03 11:40:27 2024 Strip ended Tue Sep 03 11:41:35 2024 Wafer tested in 1 minute 08 seconds Average device test 13.600 sec. time Map dimensions LowX=0, LowY=0, HighX=1, HighY=2



Run 1, Run 2,...

List of Individual Maps 50/55



| Software Binning | Bin Name | Pass/ Fail | Total count | Percentage | Software Binning Chart |
|---------------------|------------------|---------------|--------------------|------------|------------------------|
| 1 | _ | P | 5 | 100.0 % | |
| All PASS Bir | All PASS Bins | P | 5 | 100.0 % | |
| ALL Bins | ALL Bins | - | 5 | 100.0 % | |

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Software Binning Summary 51/55



| <u>Hardware</u> <u>Binning</u> | Bin Name | Pass/ Fail | Total count | Percentage | Hardware Binning Chart |
|-----------------------------------|------------------|---------------|--------------------|------------|------------------------|
| 1 | _ | P | 5 | 100.0 % | |
| All PASS Bins | All PASS Bins | P | 5 | 100.0 % | |
| ALL Bins | ALL Bins | _ | 5 | 100.0 % | |

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)



No log message to report



| Report from | Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com |
|--------------------|---|
| Report created | Mon Sep 02 23:42:12 2024 |
| Data processed | 35.3 KB (36134 bytes) |
| Processing time | 0.74 second |
| Processing speed | 48.2 KB/sec |
| Examinator expires | Sat Sep 2 2034 |
| (null) | _ |
| File name | C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/results_v2_5loop.std |
| Tests mapping file | n/a |

Global Information 52/55

| Start time Tue Sep 03 11:40:27 2024 End time Tue Sep 03 11:41:35 2024 Test duration 1 minute 08 seconds Product n/a Program rahmana_i8243_p1.igxl Revision n/a Sub-Lot n/a WaferID n/a VareTID n/a Parts processed All Data / parts (any Bin) Data from Sites All sites Test time (GODP parts) 2.029 sec. (excludes tester idle time) Test time (ALL parts) 2.029 sec. (excludes tester idle time) Average test time 1.3600 sec. / device (includes tester idle time) Total parts (vield) 5 - Includes parts retested (if any) Bad parts (Vield) (ss) 0 (0.00%) - Includes parts retested (if any) Bad parts (Vield) (ss) 0 (0.00%) - Includes parts retested (if any) Parts aborted n/a (null) - STDF Version 4.0 Tester tape UltraFLEXplus Station 1 Part type n/a Operator rahmana | Setup time | Tue Sep 03 11:40:59 2024 |
|--|---------------------------------------|--------------------------|
| End time Tue Sep 03 11:41:35 2024 Test duration 1 minute 08 seconds Product n/a Program rahmana_i8243_p1.igxl Revision n/a Lot n/a Sub-Lot n/a WaferID n/a Parts processed All Data / parts (any Bin) Data from Sites All sites Test time (GOOD parts) 2.029 sec. (excludes tester idle time) Test time (ALL parts) 2.029 sec. (excludes tester idle time) Average test time 1 3.600 sec. / device (includes tester idle time between parts) Total parts tested 5 - Includes parts retested (if any) Good parts (Yield loss) 0 (0.00%) - Includes parts retested (if any) Parts aborted 0 (0.00%) - Includes parts retested (if any) Parts aborted 0 (0.00%) (mull) - STDF Version 4.0 Tester name SNG-UFP-789 Tester type UltraFLEXplus Station 1 Part type n/a Operator rahmana < | • | • |
| Test duration 1 minute 08 seconds Product n/a Program rahmana j8243 p1.igxl Revision n/a Lot n/a Sub_Lot n/a WaferID n/a Parts processed All Data / parts (any Bin) Data from Sites All sites Test time (GOOD parts) 2.029 sec. (excludes tester idle time) Average test time 13.600 sec. / device (includes tester idle time between parts) Total parts tested 5 - Includes parts retested (if any) Good parts (Yield loss) 0 (0.00%) – Includes parts retested (if any) Parts aborted n/a . Parts aborted n/a . STDF Version 4.0 Stester name SNG_UFP-789 Tester type UttraFLEXplus Tester type UttraFLEXplus Operator rahmana Exec_type IG-XL Exec_type IG-XL Exec_type IG-XL Exec_type IG-XL Exec_type IG-XL Exec_typ | | · |
| Product n/a Program rahmana_i8243_p1.igxl Revision n/a Sub-Lot n/a WaferID n/a Parts processed All Data / parts (any Bin) Data from Sites All Sites Test time (GOD parts) 2.029 sec. (excludes tester idle time) Test time (ALL parts) 2.029 sec. (excludes tester idle time) Average test time 13.600 sec. / device (includes tester idle time between parts) Total parts tested 5 - Includes parts retested (if any) Good parts (Yield) 5 (100.00%) – Includes parts retested (if any) Bad parts (Yield loss) 0 (0.00%) – Includes parts retested (if any) Parts retested n/a Parts retested 0 (0.00%) (null) – STDF Version 4.0 Tester type UltraFLEXplus Station 1 Part type n/a Operator rahmana Exec_version 10.301.puft (P1.11) TestCode n/a Test Temperature n/a User T | | · |
| Programrahmana_i8243_p1.igxlRevisionn/aLotn/aSub-Lotn/aWaferIDn/aParts processedAll Data / parts (any Bin)Data from SitesAll SitesTest time (GOOD parts)2.029 sec. (excludes tester idle time)Test time (ALL parts)2.029 sec. (excludes tester idle time)Average test time13.600 sec. / device (includes tester idle time between parts)Total parts tested5 - Includes parts retested (if any)Good parts (Yield)5 (100.00%) - Includes parts retested (if any)Bad parts (Yield loss)0 (0.00%) - Includes parts retested (if any)Parts abortedn/a(null)-STDF Version4.0Tester nameSNG-UFP-789Tester nameSNG-UFP-789Tester typeUltraFLExplusStation1Part typen/aOperatorn/aExec_typeIG-XLExec_typeIG-XLExec_typeIncludes parts retested (if any)Test Temperaturen/aUser Testn/a | | |
| Revision n/a Lot n/a WaferID n/a Parts processed All Data / parts (any Bin) Data from Sites All sites Test time (GOOD parts) 2.029 sec. (excludes tester idle time) Test time (ALL parts) 2.029 sec. (excludes tester idle time) Average test time 13.600 sec. / device (includes tester idle time between parts) Total parts tested 5 - Includes parts retested (if any) Good parts (Yield) 5 (100.00%) - Includes parts retested (if any) Parts retested n/a Parts aborted n/a (null) - STDF Version 4. Tester name SNG-UFP-789 Tester type UltraFLExplus Station 1 Part type n/a Operator n/a Exec_type IG-XL Exec_type IG-3L Exec_type 10.30.1_uflx (P1.11) TestOde n/a TestOde n/a TestOde n/a TestOde < | | |
| Lotn/aSub-Lotn/aWaferIDn/aParts processedAll Data / parts (any Bin)Data from SitesAll sitesTest time (GOOD parts)2.029 sec. (excludes tester idle time)Test time (ALL parts)2.029 sec. (excludes tester idle time)Average test time13.600 sec. / device (includes tester idle time between parts)Total parts tested5 - Includes parts retested (if any)Good parts (Yield)5 (100.00%) - Includes parts retested (if any)Bad parts (Yield loss)0 (0.00%) - Includes parts retested (if any)Parts retestedn/aParts aborted0 (0.00%)(null)-TSTDF Version4.0Tester nameSNG-UFP-789Tester typeUltraFLEXplusStation1Part typen/aOperatorrahmanaExec_typeIG-XLExec_typeIG-XLExec_type10.30.10_uflx (P1.11)TestOden/aTest Temperaturen/aUser Textn/a | | |
| Sub-Lotn/aWaferIDn/aParts processedAll Data / parts (any Bin)Data from SitesAll sitesTest time (GODD parts)2.029 sec. (excludes tester idle time)Test time (ALL parts)2.029 sec. (excludes tester idle time)Average test time13.600 sec. / device (includes tester idle time between parts)Total parts tested5 - Includes parts retested (if any)Good parts (Yield)5 (100.00%) - Includes parts retested (if any)Bad parts (Yield loss)0 (0.00%) - Includes parts retested (if any)Parts abortedn/a(oull)-STDF Version4.0Tester nameSNG-UFP-789Tester typeUltraFLEXplusStation1Part typen/aOperatorrahmanaExec_typeIG-XLExec_typeIG-XLExec_type10.30.10_uflx (P1.11)TestCoden/aTest Temperaturen/aUser Textn/a | | |
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| Data from Sites All sites Test time (GOOD parts) 2.029 sec. (excludes tester idle time) Test time (ALL parts) 2.029 sec. (excludes tester idle time) Average test time 13.600 sec. / device (includes tester idle time between parts) Total parts tested 5 - Includes parts retested (if any) Good parts (Yield) 5 (100.00%) - Includes parts retested (if any) Parts retested n/a. Parts aborted 0 (0.00%) (null) - STDF Version 4.0 Tester name SNG-UFP-789 Tester type UltraFLEXplus Station 1 Part type n/a Operator rahmana Exec_type IG-XL Exec_version 10.30.10_uflx (P1.11) TestCode n/a Test Temperature n/a User Text n/a | | |
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| (null) - STDF Version 4.0 Tester name SNG-UFP-789 Tester type UltraFLEXplus Station 1 Part type n/a Operator rahmana Exec_type IG-XL Exec_version 10.30.10_uflx (P1.11) Test Code n/a Test Temperature n/a User Text n/a | | |
| STDF Version 4.0 Tester name SNG-UFP-789 Tester type UltraFLEXplus Station 1 Part type n/a Operator rahmana Exec_type IG-XL Exec_version 10.30.10_uflx (P1.11) TestCode n/a Test Temperature n/a User Text name SNG-UFP-789 ENG-UFP-789 IUtraFLEXplus IItraFLEXplus IIItraFLEXplus IIItraFLEXpl | (null) | |
| Tester type UltraFLEXplus Station 1 Part type n/a Operator rahmana Exec_type IG-XL Exec_version 10.30.10_uflx (P1.11) TestCode n/a Test Temperature n/a User Text n/a | | |
| Station 1 Part type n/a Operator rahmana Exec_type IG-XL Exec_version 10.30.10_uflx (P1.11) TestCode n/a Test Temperature n/a User Text n/a | Tester name | SNG-UFP-789 |
| Part type n/a Operator rahmana Exec_type IG—XL Exec_version 10.30.10_uflx (P1.11) TestCode n/a Test Temperature n/a User Text n/a | Tester type | UltraFLEXplus |
| Operator rahmana Exec_type IG-XL Exec_version 10.30.10_uflx (P1.11) TestCode n/a Test Temperature n/a User Text n/a | Station | 1 |
| Exec_type IG-XL Exec_version 10.30.10_uflx (P1.11) TestCode n/a Test Temperature n/a User Text n/a | Part type | n/a |
| Exec_version 10.30.10_uflx (P1.11) TestCode n/a Test Temperature n/a User Text n/a | Operator | rahmana |
| TestCode n/a Test Temperature n/a User Text n/a | Exec_type | IG–XL |
| Test Temperature n/a User Text n/a | Exec_version | 10.30.10_uflx (P1.11) |
| User Text n/a | TestCode | n/a |
| | Test Temperature | n/a |
| Avv. 610 | User Text | n/a |
| Aux_me n/a | Aux_file | n/a |
| Package type n/a | Package type | n/a |
| Per_freq n/a | Per_freq | n/a |
| Spec_name n/a | Spec_name | n/a |
| Spec_version n/a | Spec_version | n/a |
| Family ID n/a | Family ID | n/a |

Global Information 53/55

| Date code | n/a |
|-----------------|---------|
| Design Rev | n/a |
| Facility ID | n/a |
| Floor ID | n/a |
| Proc ID | n/a |
| Flow ID | n/a |
| Setup ID | n/a |
| Eng ID | n/a |
| ROM code | n/a |
| Serial # | n/a |
| Super user name | n/a |
| Handler/Prober | n/a |
| (null) | - |
| Site details | Site# 0 |

Global Information 54/55



| Test# policy | Never merge tests with identical test number if test name not matching |
|------------------------|--|
| Data Cleaning | None (keep all data) |
| Statistics computation | From samples data (if any), otherwise from summary |
| Binning computation | From summary data (if any), otherwise from samples |
| Cp,Cpk computation | Use standard Sigma formula |
| Mean drift formula | Percentage of value drift |

Global Options 55/55